

<<VLSI的统计分析和优化>>

图书基本信息

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内容概要

该书介绍了集成电路的统计CAD工具的相关知识。

主要面向CAD工具开发人员、集成电路工艺技术人员，以及相关学科的学生和研究人员。

书中介绍了统计时序和功耗分析技术中的最新研究成果，并结合参数化的产量作为设计过程中的主要目标函数。

该书强调算法、过程变量的建模方法，以及统计方法。

既可作为刚涉足CAD工具开发领域的人员的入门书籍，也可作为该领域工程师的参考手册。

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